

**Search Notes**

Application/Control No.

10/801,219

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

MEGAW ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	312		
	313		
	314		
	315		
	316		
	907		
341	119		
327	539	1/09	JA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR